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FDS4501H

Complementary PowerTrench Half-Bridge MOSFET

General Description

This complementary MOSFET half-bridge device is produced using Fairchild's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain low gate charge for superior switching performance.

Applications

- DC/DC converter
- Power management
- · Load switch
- · Battery protection

Features

Q1: N-Channel

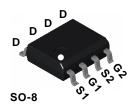
9.3A, 30V
$$R_{DS(on)} = 18 \text{ m}\Omega @ V_{GS} = 10V$$

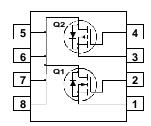
$$R_{DS(on)} = 23 \text{ m}\Omega @ V_{GS} = 4.5V$$

Q2: P-Channel

$$-5.6A, -20V$$
 $R_{DS(on)} = 46 \text{ m}\Omega @ V_{GS} = -4.5V$

$$R_{DS(on)} = 63 \text{ m}\Omega @ V_{GS} = -2.5V$$





Absolute Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter		Q1	Q1 Q2	
V _{DSS}	Drain-Source Voltage		30	-20	V
V _{GSS}	Gate-Source Voltage		±20	±8	V
I _D	Drain Current - Continuous	(Note 1a)	9.3	-5.6	А
	- Pulsed		20	-20	
P_D	Power Dissipation for Single Operation	(Note 1a)	2.	.5	W
		(Note 1b)	1.	.2	
		(Note 1c)	,	1	
T _J , T _{STG}	Operating and Storage Junction Temperature Range		–55 to	°C	

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	50	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	(Note 1)	25	°C/W

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
FDS4501H	FDS4501H	13"	12mm	2500 units

Symbol	Parameter	Test Conditions	Туре	Min	Тур	Max	Units
Off Char	acteristics					-	
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$ $V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	Q1 Q2	30 –20			V
<u>ΔBV_{DSS}</u> ΔT _J	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu\text{A}$, Referenced to 25°C $I_D = -250 \mu\text{A}$, Referenced to 25°C	Q1 Q2		24 -13		mV/°C
l _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 24 V, V _{GS} = 0 V V _{DS} = -16 V, V _{GS} = 0 V	Q1 Q2			1 –1	μΑ
l _{GSS}	Gate-Body Leakage	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$ $V_{GS} = \pm 8 \text{ V}, V_{DS} = 0 \text{ V}$	Q1 Q2			<u>+</u> 100 <u>+</u> 100	nA
On Char	acteristics (Note 2)						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$ $V_{DS} = V_{GS}, I_D = -250 \mu A$	Q1 Q2	1 -0.4	1.6 -0.7	3 –1.5	V
$\Delta V_{GS(th)} \over \Delta T_{,J}$	Gate Threshold Voltage Temperature Coefficient	$I_D = 250 \mu\text{A}$, Referenced to 25°C $I_D = -250 \mu\text{A}$, Referenced to 25°C	Q1 Q2		-4 3		mV/°C
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 9.3 A V _{GS} = 10 V, I _D = 9.3 A, T _J = 125°C V _{GS} = 4.5 V, I _D = 7.6 A	Q1		14 21 17	18 29 23	mΩ
		$V_{GS} = -4.5 \text{ V}, I_D = -5.6 \text{ A}$ $V_{GS} = -4.5 \text{ V}, I_D = -5.6 \text{ A}, T_J = 125^{\circ}\text{C}$ $V_{GS} = -2.5 \text{ V}, I_D = -5.0 \text{ A}$	Q2		36 49 47	46 80 63	
D(on)	On-State Drain Current	$V_{GS} = 10 \text{ V}, V_{DS} = 5 \text{ V}$ $V_{GS} = -4.5 \text{ V}, V_{DS} = -5 \text{ V}$	Q1 Q2	20 –20			Α
g FS	Forward Transconductance	$V_{DS} = 5 \text{ V}, I_{D} = 9.3 \text{ A}$ $V_{DS} = 5 \text{ V}, I_{D} = -5.6 \text{ A}$	Q1 Q2		28 16		S
Dynamic	Characteristics						
C _{iss}	Input Capacitance	$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz	Q1 Q2		1958 1312		pF
Coss	Output Capacitance		Q1 Q2		424 240		pF
C _{rss}	Reverse Transfer Capacitance		Q1 Q2		182 106		pF

Electrical Characteristics (continued)

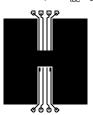
 $T_A = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Туре	Min	Тур	Max	Units	
Switchin	Switching Characteristics (Note 2)							
t _{d(on)}	Turn-On Delay Time	Q1 $V_{DD} = 15 \text{ V}, I_D = 1 \text{ A},$	Q1 Q2		15 15	27 27	ns	
t _r	Turn-On Rise Time	V_{GS} = 10V, R_{GEN} = 6 Ω	Q1 Q2		5 15	10 27	ns	
t _{d(off)}	Turn-Off Delay Time	$V_{DD} = -10 \text{ V}, I_{D} = -1 \text{ A},$ $V_{GS} = -4.5 \text{ V}, R_{GEN} = 6 \Omega$	Q1 Q2		38 40	61 64	ns	
t _f	Turn-Off Fall Time		Q1 Q2		10 25	20 40	ns	
Qg	Total Gate Charge	Q1 $V_{DS} = 15 \text{ V}, I_D = 9.3 \text{ A}, V_{GS} = 4.5 \text{ V}$	Q1 Q2		17 13	27 21	nC	
Q_{gs}	Gate-Source Charge	Q2	Q1 Q2		4 2.5		nC	
Q_{gd}	Gate-Drain Charge	$V_{DS} = 15 \text{ V}, I_{D} = -2.4 \text{ A}, V_{GS} = -4.5 \text{ V}$	Q1 Q2		5 2.0		nC	
Drain-Sc	ource Diode Characteri	stics and Maximum Ratings						
1	Maximum Continuous Drain-Source Diode Forward Current		Q1			2.1	Α	

Notes:

 V_{SD}

 $V_{GS} = 0 \text{ V}, I_{S} = -2.1 \text{ A}$ (Note 2)



a) 50°C/W when mounted on a 1 in² pad of 2 oz



Drain-Source Diode Forward $V_{GS} = 0 \text{ V}$, $I_S = 2.1 \text{ A}$ (Note 2)

b) 105°C/W when mounted on a 0.04 in² pad of 2 oz copper



Q2

Q1

Q2

c) 125°C/W when mounted on a minimum pad.

-2.1

1.2

-1.2

Scale 1:1 on letter size paper

2. Pulse Test: Pulse Width < 300µs, Duty Cycle < 2.0%

^{1.} R_{BJA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.

Typical Characteristics: Q2

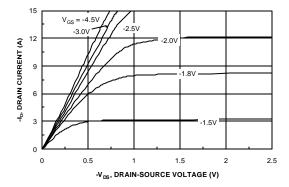


Figure 1. On-Region Characteristics.

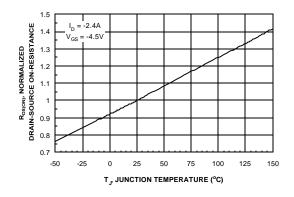


Figure 3. On-Resistance Variation with Temperature.

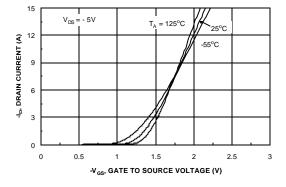


Figure 5. Transfer Characteristics.

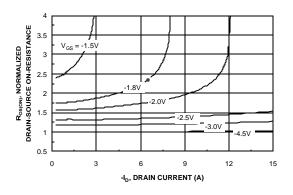


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

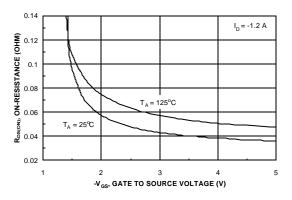


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

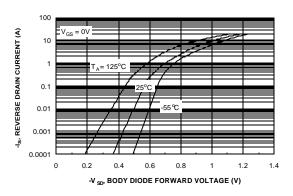
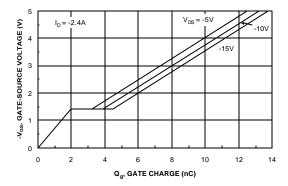


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics: Q2



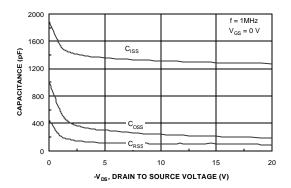
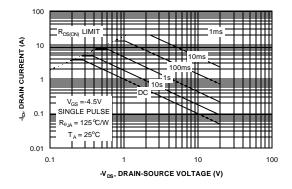


Figure 7. Gate Charge Characteristics.

Figure 8. Capacitance Characteristics.



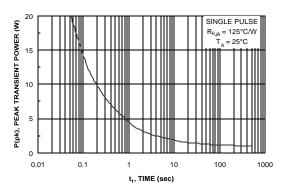


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

Typical Characteristics: Q1

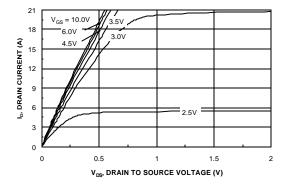


Figure 11. On-Region Characteristics.

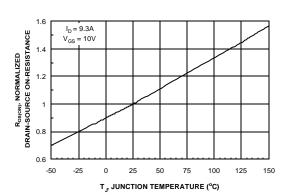


Figure 13. On-Resistance Variation with Temperature.

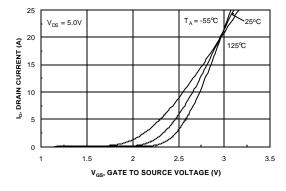


Figure 15. Transfer Characteristics.

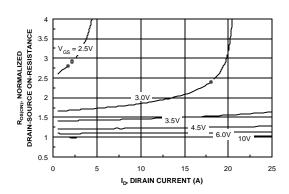


Figure 12. On-Resistance Variation with Drain Current and Gate Voltage.

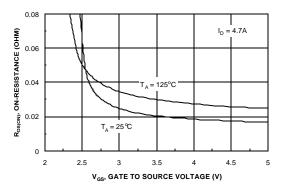


Figure 14. On-Resistance Variation with Gate-to-Source Voltage.

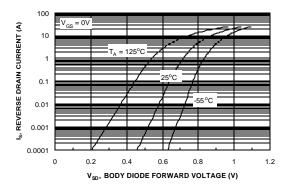
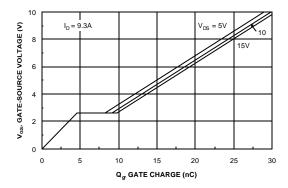


Figure 16. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics Q1



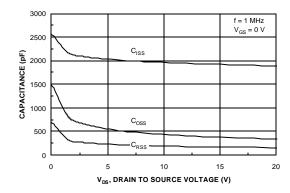
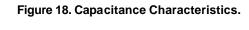
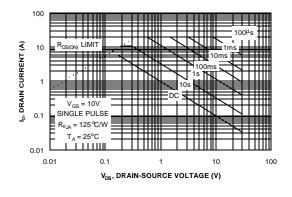


Figure 17. Gate Charge Characteristics.





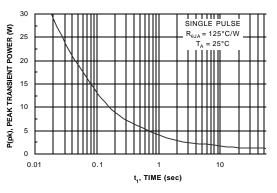


Figure 19. Maximum Safe Operating Area.

Figure 20. Single Pulse Maximum Power Dissipation.

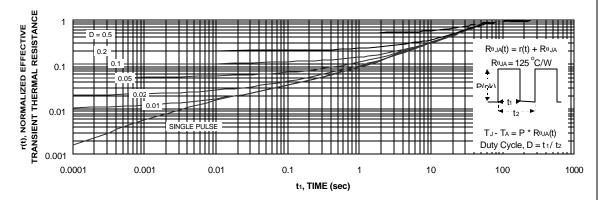


Figure 21. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.

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